



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002-02

CB Certificate No.: JQAQ0002-003-T

Schedule Number: IECQ-L JQAJP 13.0002-02-S Rev No.: 2 Revision Date: 2016/12/22 Page 1 of 4

TESTD PARTS

Fixed capacitor, Fixed resistor, Potentiometer, Varistor, Thermistor, Connector, Relay, Switch, Printed circuit board, Semiconductor Devices, Semiconductor Integrated Circuit and Optical Component

ENVIRONMENTAL TEST

IEC 60068-2-1:2013	Cold
IEC 60068-2-2:2007	Dry heat
IEC 60068-2-11:1981	Salt mist
IEC 60068-2-13:1983	Low air pressure
IEC 60068-2-14:2009	Change of temperature
IEC 60068-2-18:2000	Test R and guidance: Water
IEC 60068-2-20:2008	Test methods for solderability and resistance to soldering heat of devices with leads
IEC 60068-2-30:2005	Damp heat, cyclic (12+12-hour cycle)
IEC 60068-2-38:2009	Composite temperature/humidity cyclic test
IEC 60068-2-40:1976	Combined cold/low air pressure tests
IEC 60068-2-41:1976	Combined dry heat/low air pressure tests
JIS C 60068-2-42:1993	Sulphur dioxide test for contacts and connections
JIS C 60068-2-43:1993	Hydrogen sulphide test for contacts and connections
IEC 60068-2-52:1996	Salt mist, cyclic (sodium chloride solution)
IEC 60068-2-54:2006	Soldering. Solderability testing by the wetting balance method
IEC 60068-2-58:2004	Test methods for solderability, resistance to dissolution of metallization and to soldering heat of SMD
IEC 60068-2-60:1995	Flowing mixed gas corrosion test
IEC 60068-2-66:1994	Damp heat, steady state (unsaturated pressurized vapour)
IEC 60068-2-69:2007	Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method
IEC 60068-2-78:2012	Damp heat, steady state

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org



Japan Quality Assurance Organization (JQA)
4-4-4, Minamiosawa, Hachioji-shi, Tokyo 192-0364 Japan



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002-02

CB Certificate No.: JQAQ0002-003-T

Schedule Number: IECQ-L JQAJP 13.0002-02-S Rev No.: 2 Revision Date: 2016/12/22 Page 2 of 4

IEC 60068-2-83:2011	Solderability testing of electronic components for surface mounting devices (SMD) by the wetting balance method using solder paste
EIAJ ET-7404:1997	Solderability testing of electronic components for surface mount technology by the wetting balance method with solder paste
JIS D 0205:1987	Test method of weatherability for automotive parts
MIL STD 202G	Test method standard electronic and electrical component parts
MIL STD 883J	Test method standard microcircuits

MECHANICAL TEST

IEC 60068-2-6:2007	Vibration (sinusoidal)
IEC 60068-2-7:1983	Acceleration, steady state
IEC 60068-2-27:2008	Shock
IEC 60068-2-31:2008	Rough handling shocks, primarily for equipment-type specimens
IEC 60068-2-64:2008	Vibration, broadband random and guidance
JIS C 60068-2-75:2004	Hammer tests

FIRE HAZARD TEST

IEC 60695-2-10:2013	Glowing/hot-wire based test methods – Glow-wire apparatus and common test procedure
JIS C 60695-2-11:2004	Glow-wire flammability test method for end-products
JIS C 60695-2-12:2010	Glowing/hot-wire based test methods – Glow-wire flammability index (GWFI) test method for materials
JIS C 60695-2-13:2010	Glowing/hot-wire based test methods – Glow-wire ignition temperature (GWIT) test method for materials
IEC 60695-11-5:2004	Test flames - Needle-flame test method – Apparatus, confirmatory test arrangement and guidance

This schedule is only valid in conjunction with the referenced Certificate of Approval
This approval and any schedule(s) may only be reproduced in full.
This approval is not transferable and remains the property of the issuing body.
The Status and authenticity of this approval and any schedule(s) may be verified by visiting the
Official IECQ Website. www.iecq.org



Japan Quality Assurance Organization (JQA)
4-4-4, Minamiosawa, Hachioji-shi, Tokyo 192-0364 Japan



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002-02

CB Certificate No.: JQAQ0002-003-T

Schedule Number: IECQ-L JQAJP 13.0002-02-S Rev No.: 2 Revision Date: 2016/12/22 Page 3 of 4

MEASUREMENT RANGE

Passive component

Type / Part name	Measurable property value	: Measuring range
Fixed resistor	(1)Resistance value	: 1Ω~100MΩ
	(2)Resistance temperature properties and gap of the resistance level.	: Temperature range -55℃~+150℃
	(3)Insulation resistance	: 5×10 ⁵ Ω~2×10 ¹⁴ Ω
	(4)Voltage endurance	: AC,DC 0~5KV
Variable resistor [potentiometer]	(1)Resistance value	: 1Ω~100MΩ
	(2)Mutual deviations	: ±3%
	(3)Resistance temperature properties and gap of the resistance level.	: Temperature range -40℃~+150℃
	(4)Insulation resistance	: 5×10 ⁵ Ω~10 ¹⁴ Ω
	(5)Voltage endurance	: AC,DC 0~5KV
	(6)Rotational noise	: Noise voltage 1mV
	(7)Intensive contact resistance	: 1mΩ
Variable resistor	Voltage at reference current	: 1500V(1mA min)

Mechanical device

Type / Part name	Measurable property value	: Measuring range
Connector (Electronic equipment use)	(1)Insulation resistance	: 5×10 ⁵ Ω~2×10 ¹⁴ Ω
	(2)Withstand voltage	: AC,DC 0~5KV
	(3)Contact resistance under low voltage, the low electric current.	: 1mΩ~100Ω
	(4)Chattering of the contact.	: 1μsec max
Relay (Small form for control)	(1)Withstand voltage	: AC,DC 0~5KV
	(2)Insulation resistance	: 5×10 ⁵ Ω~2×10 ¹⁴ Ω
	(3)Direct current resistance of the coil	: 1Ω~10KΩ
	(4)Contact resistance	: 1mΩ~100Ω
	(5)Operating voltage	: 1V max
	(6)Must-release voltage	: 1V max
	(7)Operation time	: 1msec max
	(8)Recovery time	: 1msec max
	(9)Bounces of the point of contact	: 1μsec max
	(10)Chattering of the point of contact	: 1μsec max
Switch (Electronic equipment use)	(1)Contact resistance	: 1mΩ~100Ω
	(2)Insulation resistance	: 5×10 ⁵ Ω~2×10 ¹⁴ Ω
	(3)Withstand voltage	: AC,DC 0~5KV
	(4)Change of the contact resistance	: 1mΩ max

This schedule is only valid in conjunction with the referenced Certificate of Approval

This approval and any schedule(s) may only be reproduced in full.

This approval is not transferable and remains the property of the issuing body.

The Status and authenticity of this approval and any schedule(s) may be verified by visiting the

Official IECQ Website. www.iecq.org



Japan Quality Assurance Organization (JQA)
 4-4-4, Minamiosawa, Hachioji-shi, Tokyo 192-0364 Japan



Schedule of Scope to Certificate of Approval Independent Testing Laboratory

IECQ Certificate No.: IECQ-L JQAJP 13.0002-02

CB Certificate No.: JQAQ0002-003-T

Schedule Number: IECQ-L JQAJP 13.0002-02-S Rev No.: 2 Revision Date: 2016/12/22 Page 4 of 4

MEASUREMENT RANGE

Printed circuit board

Type / Part name	Measurable property value	: Measuring range
Printed circuit board	(1)Resistance of the plating part of the conductor and through hall part.	: 1mΩ~1000Ω
	(2)Withstand voltage	: AC,DC 0~5KV
	(3)Insulation resistance	: 5×10 ⁵ Ω~10 ¹⁴ Ω

This schedule is only valid in conjunction with the referenced Certificate of Approval

This approval and any schedule(s) may only be reproduced in full.

This approval is not transferable and remains the property of the issuing body.

The Status and authenticity of this approval and any schedule(s) may be verified by visiting the

Official IECQ Website. www.iecq.org



Japan Quality Assurance Organization (JQA)
4-4-4, Minamiosawa, Hachioji-shi, Tokyo 192-0364 Japan